

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	33	(quiescent adj current or iddq) near10 location and test and integrated adj circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/28 08:21
L5	223	((iddq or quiescent adj current) and (pin or terminal) and (location or area) and defect and integrated adj circuit)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/28 08:32

FOR Interference Search

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	0	((iddq or quiescent adj current) and (pin or terminal) and (location or area) and defect and integrated adj circuit).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/28 08:10
L3	7	(terminal and location and defect and map).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/28 08:15